MJD200 (NPN), MJD210, NJVMJD210T4G (PNP)

Complementary Plastic Power Transistors

NPN/PNP Silicon DPAK For Surface Mount Applications

Designed for low voltage, low−power, high−gain audio amplifier applications.

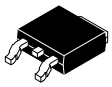
Features

- Collector−Emitter Sustaining Voltage −
  $V_{CEO(sus)}$ = 25 Vdc (Min) @ I_C = 10 mAdc
- High DC Current Gain − h_{FE} = 70 (Min) @ I_C = 500 mAdc
  = 45 (Min) @ I_C = 2 Adc
  = 10 (Min) @ I_C = 5 Adc
- Lead Formed for Surface Mount Applications in Plastic Sleeves (No Suffix)
- Low Collector−Emitter Saturation Voltage −
  $V_{CE(sat)}$ = 0.3 Vdc (Max) @ I_C = 500 mAdc
  = 0.75 Vdc (Max) @ I_C = 2.0 Adc
- High Current−Gain − Bandwidth Product −
  f_T = 65 MHz (Min) @ I_C = 100 mAdc
- Annular Construction for Low Leakage −
  I_{CBO} = 100 nAdc @ Rated V_{CB}
- Epoxy Meets UL 94 V−0 @ 0.125 in
- ESD Ratings:
  - Human Body Model, 3B > 8000 V
  - Machine Model, C > 400 V
- NJV Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC−Q101 Qualified and PPAP Capable
- These are Pb−Free Packages*

ON Semiconductor®

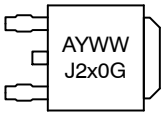
http://onsemi.com

SILICON
POWER TRANSISTORS
5 AMPERES
25 VOLTS, 12.5 WATTS



DPAK
CASE 369C
STYLE 1

MARKING DIAGRAM



A = Assembly Location
Y = Year
WW = Work Week
x = 1 or 0
G = Pb−Free Package

ORDERING INFORMATION

See detailed ordering and shipping information in the package dimensions section on page 3 of this data sheet.

*For additional information on our Pb−Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

February, 2012 − Rev. 12
Publication Order Number:
MJD200/D

MAXIMUM RATINGS

Rating	Symbol	Max	Unit
Collector−Base Voltage	V_{CB}	40	Vdc
Collector−Emitter Voltage	V_{CEO}	25	Vdc
Emitter−Base Voltage	V_{EB}	8.0	Vdc
Collector Current Continuous Peak	I_C	 5.0 10	Adc
Base Current	I_B	1.0	Adc
Total Power Dissipation @ T_C = 25°C Derate above 25°C	P_D	 12.5 0.1	 W W/°C
Total Power Dissipation (Note 1) @ T_A = 25°C Derate above 25°C	P_D	 1.4 0.011	 W W/°C
Operating and Storage Junction Temperature Range	T_J, T_{stg}	−65 to +150	°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

1. These ratings are applicable when surface mounted on the minimum pad sizes recommended.

THERMAL CHARACTERISTICS

Characteristic	Symbol	Max	Unit
Thermal Resistance, Junction−to−Case	$R_{\theta JC}$	10	°C/W
Thermal Resistance, Junction−to−Ambient (Note 2)	$R_{\theta JA}$	89.3	°C/W

2. These ratings are applicable when surface mounted on the minimum pad sizes recommended.

ELECTRICAL CHARACTERISTICS (T_C = 25°C unless otherwise noted)

Characteristic	Symbol	Min	Max	Unit
OFF CHARACTERISTICS				
Collector−Emitter Sustaining Voltage (Note 3), (I_C = 10 mAdc, I_B = 0)	$V_{CEO(sus)}$	25	−	Vdc
Collector Cutoff Current (V_{CB} = 40 Vdc, I_E = 0) (V_{CB} = 40 Vdc, I_E = 0, T_J = 125°C)	V_{CBO}	 − −	 100 100	 nAdc μAdc
Emitter Cutoff Current (V_{BE} = 8 Vdc, I_C = 0)	V_{EBO}	−	100	nAdc
ON CHARACTERISTICS				
C Current Gain (Note 3), (I_C = 500 mAdc, V_{CE} = 1 Vdc) (I_C = 2 Adc, V_{CE} = 1 Vdc) (I_C = 5 Adc, V_{CE} = 2 Vdc)	h_{FE}	 70 45 10	 − 180 −	−
Collector−Emitter Saturation Voltage (Note 3) (I_C = 500 mAdc, I_B = 50 mAdc) (I_C = 2 Adc, I_B = 200 mAdc) (I_C = 5 Adc, I_B = 1 Adc)	$V_{CE(sat)}$	 − − −	 0.3 0.75 1.8	Vdc
Base−Emitter Saturation Voltage (Note 3), (I_C = 5 Adc, I_B = 1 Adc)	$V_{BE(sat)}$	−	2.5	Vdc
Base−Emitter On Voltage (Note 3), (I_C = 2 Adc, V_{CE} = 1 Vdc)	$V_{BE(on)}$	−	1.6	Vdc
DYNAMIC CHARACTERISTICS				
Current−Gain − Bandwidth Product (Note 4) (I_C = 100 mAdc, V_{CE} = 10 Vdc, f_{test} = 10 MHz)	f_T	 65	 −	MHz
Output Capacitance (V_{CB} = 10 Vdc, I_E = 0, f = 0.1 MHz) MJD200 MJD210, NJVMJD210T4G	C_{ob}	 − −	 80 120	pF

3. Pulse Test: Pulse Width = 300 μs, Duty Cycle ≈ 2%.
4. $f_T = |h_{fe}| \bullet f_{test}$.

ORDERING INFORMATION

Device	Package Type	Shipping†
MJD200G	DPAK (Pb−Free)	75 Units / Rail
MJD200RLG	DPAK (Pb−Free)	1,800 / Tape & Reel
MJD200T4G	DPAK (Pb−Free)	2,500 / Tape & Reel
MJD210G	DPAK (Pb−Free)	75 Units / Rail
MJD210RLG	DPAK (Pb−Free)	1,800 / Tape & Reel
MJD210T4	DPAK	2,500 / Tape & Reel
MJD210T4G	DPAK (Pb−Free)	2,500 / Tape & Reel
NJVMJD210T4G	DPAK (Pb−Free)	2,500 / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

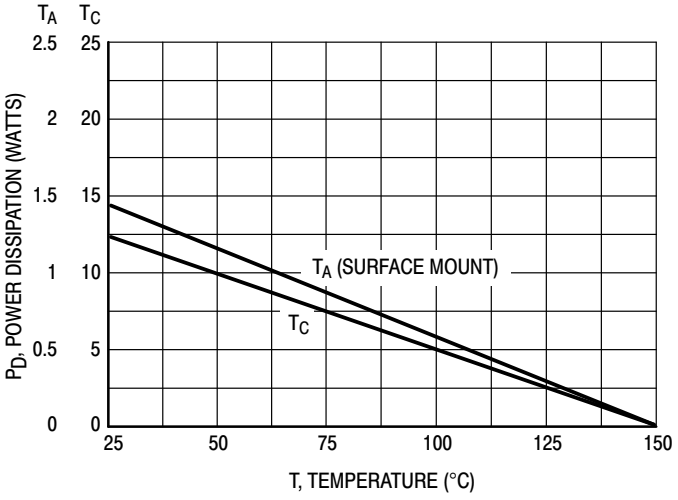


Figure 1. Power Derating

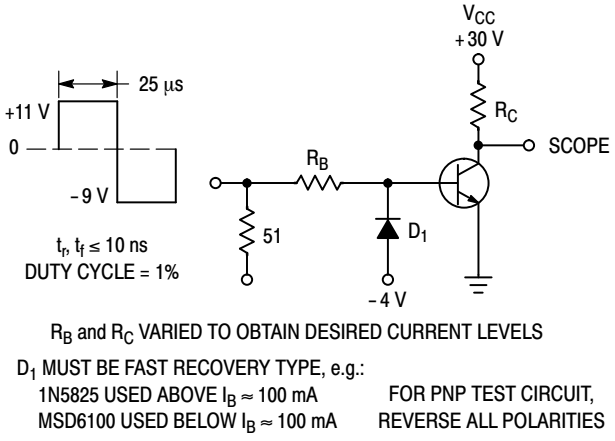


Figure 2. Switching Time Test Circuit

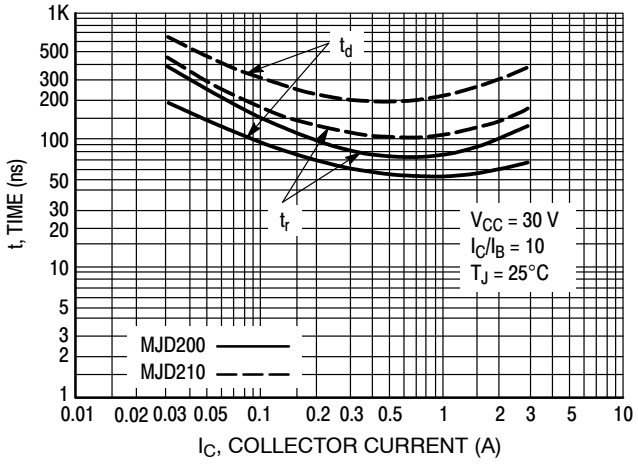


Figure 3. Turn−On Time

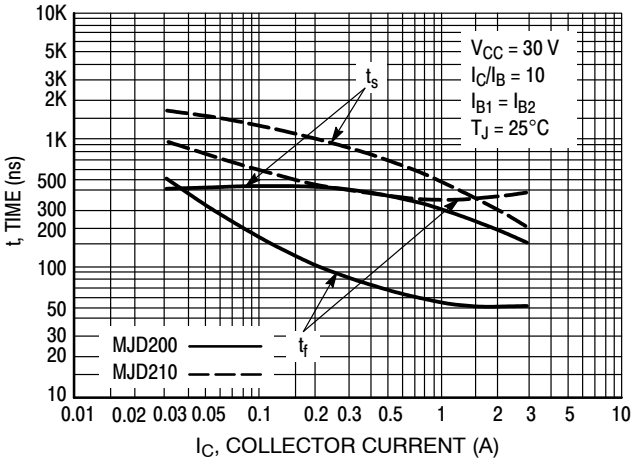
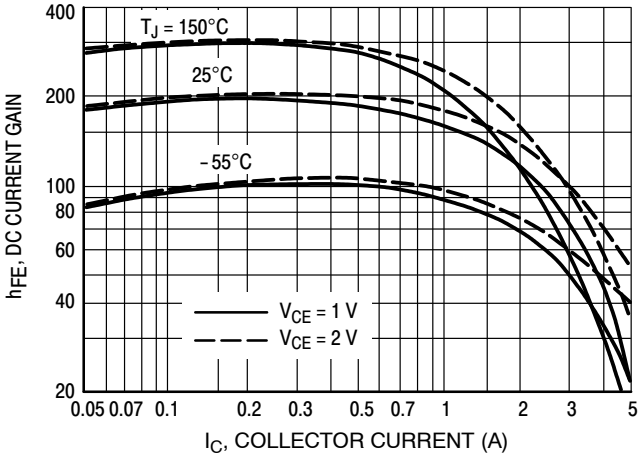


Figure 4. Turn−Off Time

NPN
MJD200



PNP
MJD210

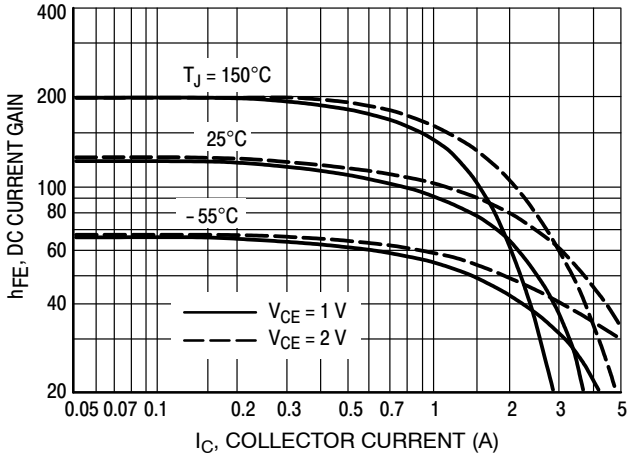
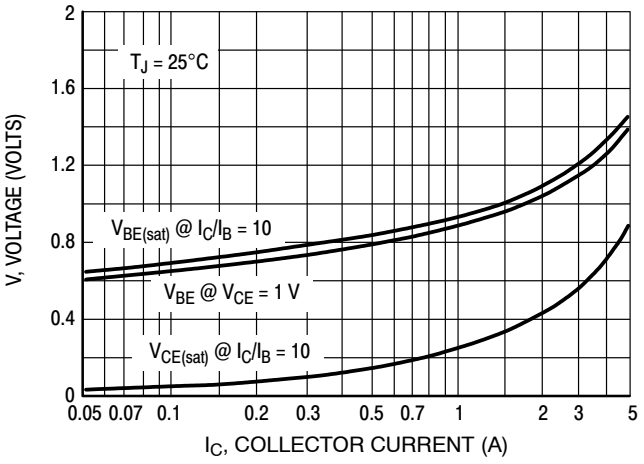


Figure 5. DC Current Gain



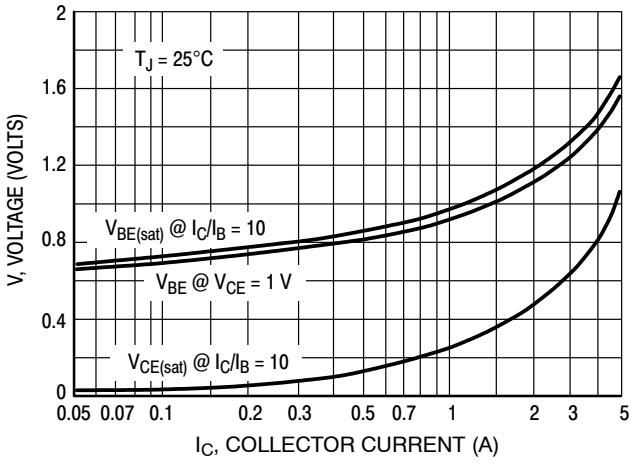
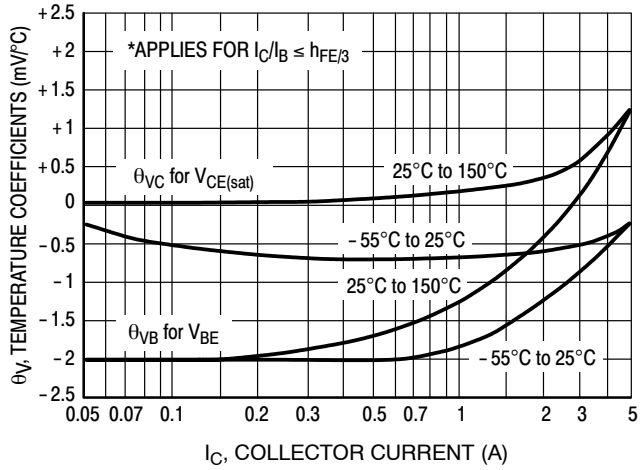


Figure 6. “On” Voltage



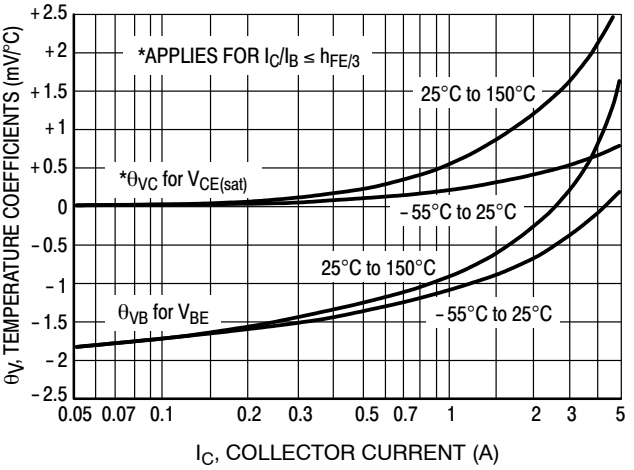


Figure 7. Temperature Coefficients

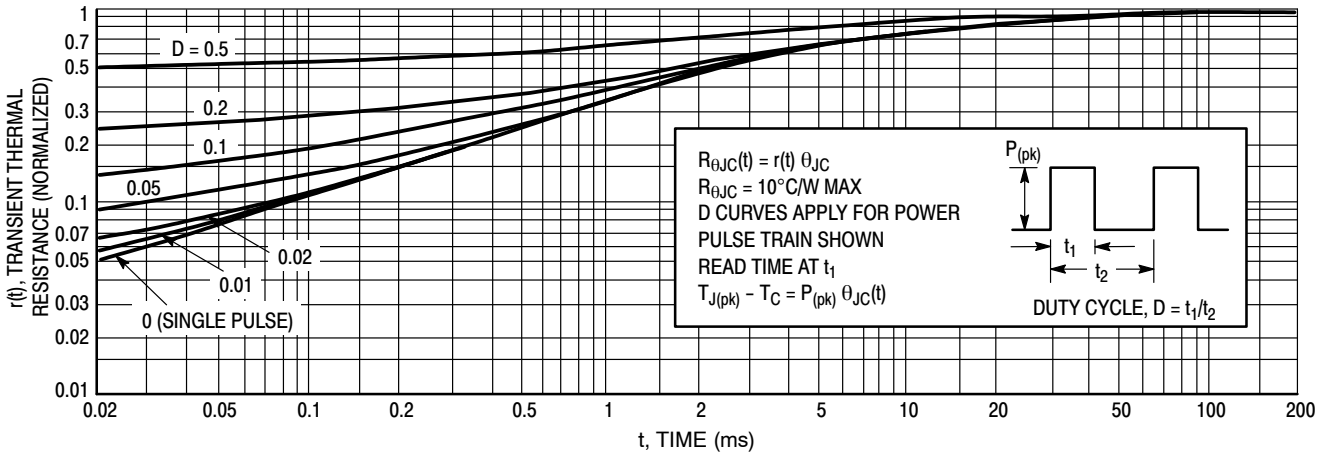


Figure 8. Thermal Response

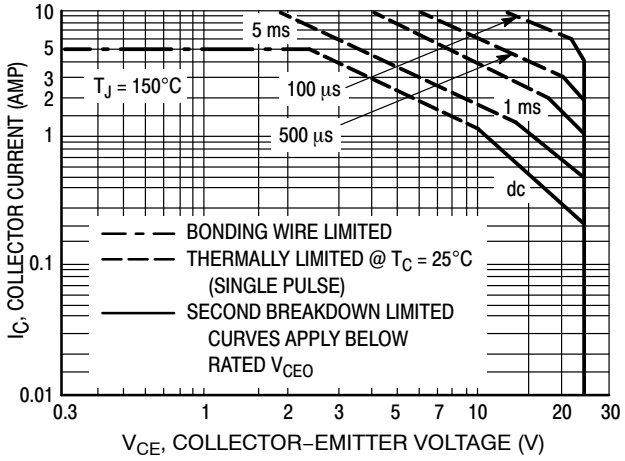


Figure 9. Active Region Safe Operating Area

There are two limitations on the power handling ability of a transistor: average junction temperature and second breakdown. Safe operating area curves indicate $I_C - V_{CE}$ limits of the transistor that must be observed for reliable operation; i.e., the transistor must not be subjected to greater dissipation than the curves indicate.

The data of Figure 9 is based on $T_{J(pk)}$ = 150°C; T_C is variable depending on conditions. Second breakdown pulse limits are valid for duty cycles to 10% provided $T_{J(pk)} \leq 150°C$. $T_{J(pk)}$ may be calculated from the data in Figure 8. At high case temperatures, thermal limitations will reduce the power that can be handled to values less than the limitations imposed by second breakdown.

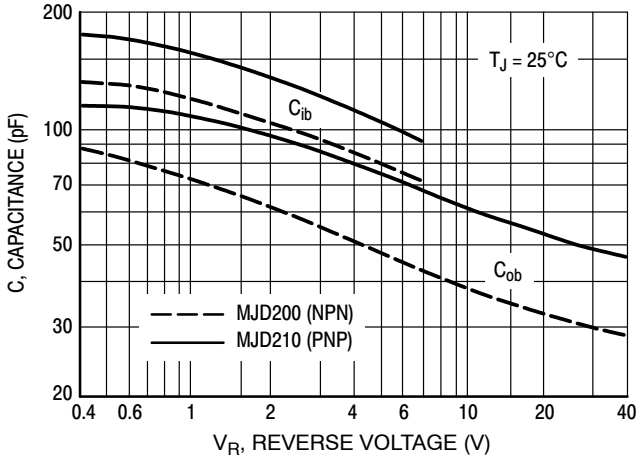
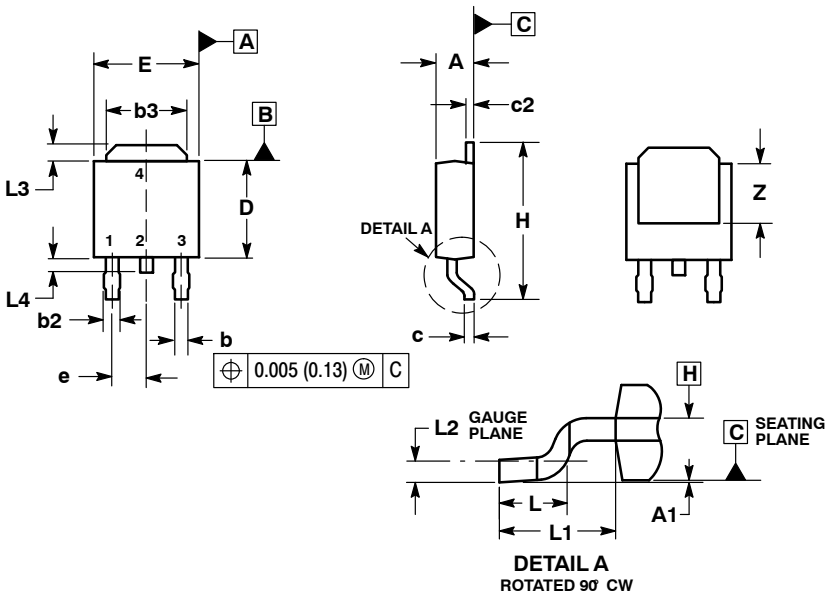


Figure 10. Capacitance

PACKAGE DIMENSIONS

DPAK
CASE 369C−01
ISSUE D

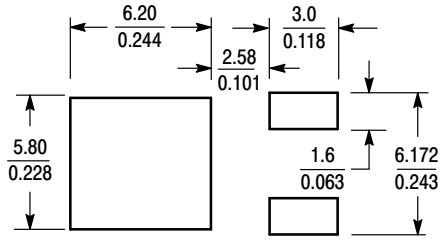


NOTES:
1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
2. CONTROLLING DIMENSION: INCHES.
3. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSIONS b3, L3 and Z.
4. DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR BURRS. MOLD FLASH, PROTRUSIONS, OR GATE BURRS SHALL NOT EXCEED 0.006 INCHES PER SIDE.
5. DIMENSIONS D AND E ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
6. DATUMS A AND B ARE DETERMINED AT DATUM PLANE H.

	INCHES		MILLIMETERS	
DIM	MIN	MAX	MIN	MAX
A	0.086	0.094	2.18	2.38
A1	0.000	0.005	0.00	0.13
b	0.025	0.035	0.63	0.89
b2	0.030	0.045	0.76	1.14
b3	0.180	0.215	4.57	5.46
c	0.018	0.024	0.46	0.61
c2	0.018	0.024	0.46	0.61
D	0.235	0.245	5.97	6.22
E	0.250	0.265	6.35	6.73
e	0.090 BSC		2.29 BSC	
H	0.370	0.410	9.40	10.41
L	0.055	0.070	1.40	1.78
L1	0.108 REF		2.74 REF	
L2	0.020 BSC		0.51 BSC	
L3	0.035	0.050	0.89	1.27
L4	−−−	0.040	−−−	1.01
Z	0.155	−−−	3.93	−−−

STYLE 1:
PIN 1. BASE
2. COLLECTOR
3. EMITTER
4. COLLECTOR

SOLDERING FOOTPRINT*



SCALE 3:1 (mm / inches)

*For additional information on our Pb−Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

PUBLICATION ORDERING INFORMATION

LITERATURE FULFILLMENT:
Literature Distribution Center for ON Semiconductor
P.O. Box 5163, Denver, Colorado 80217 USA
Phone: 303−675−2175 or 800−344−3860 Toll Free USA/Canada
Fax: 303−675−2176 or 800−344−3867 Toll Free USA/Canada
Email: orderlit@onsemi.com

N. American Technical Support: 800−282−9855 Toll Free USA/Canada
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MJD200/D